

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/663,709	FUJITA, HIROYUKI	
Examiner	Art Unit	
Anish Gupta	1654	

	SEARCHED					
Class	Subclass	Date	Examiner			
NONE						
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
search update on STN, data bases USPAT, USPGPUB, EPO, JPO, DERWENT. STN databases index bioscience	8/3/2004	AG
inventor search update on STN, data bases USPAT, USPGPUB, EPO, JPO, DERWENT. STN databases index bioscience	8/3/2004	AG